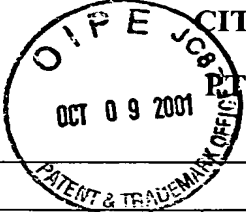


INFORMATION DISCLOSURE CITATION PTO-1449		ATTY. DOCKET NO. 8003-387		SERIAL NO. 09/895,786			
		APPLICANT Emir Gurer, et al.					
		FILING DATE 6/30/01		GROUP 1762			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
26	5,158,860	10/1992	Gulla et al	430	315		
1	5,180,431	1/1993	Sugimoto et al	118	52		
1	5,198,034	3/1993	DeBoer et al	118	500		
1	5,238,713	8/1993	Sago et al	427	348 X		
4	5,472,502	12/1995	Batchelder	118	52		
FOREIGN PATENT DOCUMENTS							
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26	0176119	8/1986	Japan	118	63	<input type="checkbox"/>	<input type="checkbox"/>
1	0206224	9/1986	Japan	118	52	<input type="checkbox"/>	<input type="checkbox"/>
1	0092316	4/1987	Japan	118	52	<input type="checkbox"/>	<input type="checkbox"/>
1	0095626	4/1988	Japan	118	52	<input type="checkbox"/>	<input type="checkbox"/>
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1	3175617	7/1991	Japan			<input type="checkbox"/>	<input type="checkbox"/>
4	6-170316	6/1994	Japan	118	52	<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
26	Van Zant, Peter, " Microchip Fabrication. A practical Guide to Semiconductor Processing." Published, 1986 by Semiconductor Services, San Jose, Calif., pp. 116-117.						
26	Wolf, Stanley Ph.D and Tauber, Richard N. Ph.D., Silicon Processing For the VLSI Era, vol. 1: Process Technology, published by Lattice Press, Calif., pp. 429-430						
				RECEIVED			
				JAN 07 2003			
EXAMINER <i>K. Purnan</i>			DATE CONSIDERED 3/4/02 TC 1700				


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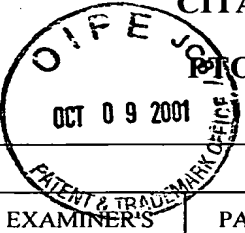
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FILING DATE 06/30/2001		GROUP 1762					
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24	5,670,210	9/23/1997	Mandal, et al.	427	240	12/1/1995	
	5,762,709	6/9/1998	Sugimoto, et al.	118	52	7/16/1996	
	4,451,507	5/29/1984	Beltz, et al.	427	240	10/29/1982	
	6,238,735	5/29/2001	Mandal, et al.	427	240	9/8/1999	
	5,954,878	9/21/1999	Mandal, et al.	118	319	6/16/1997	
	5,532,192	7/2/1996	Adams	437	229	12/14/1994	
	5,127,362	7/7/1992	Iwatsu, et al.	118	667	5/21/1990	
	5,134,962	8/4/1992	Amada, et al.	118	688	5/16/1990	
24	5,135,608	8/4/1992	Okutani	156	643	7/10/1990	
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24	279033	5/23/1990	Germany	C30	B31/00	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	46-10790	3/1971	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
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	57-45369	3/1982	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
	57-130432	8/1982	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
	60-10248	1/1985	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
	60-226125	11/1985	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
24	61-29125	2/1986	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>H. P. ...</i>				DATE CONSIDERED <i>3/6/03</i>			

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		APPLICANT Emir Gurer					
		FILING DATE 06/30/2001		GROUP 1762			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
2	5,395,803	3/7/1995	Adams	437	229	9/8/1993	
	5,449,405	9/12/1995	Cardinali, et al.	118	50	3/22/1993	
	5,472,502	12/5/1995	Batchelder	118	52	8/30/1993	
	4,113,492	9/12/1978	Sato, et al.	96	67	4/8/1977	
	4,132,357	1/2/1979	Blackinton	239	11	6/23/1976	
	4,068,019	1/10/1978	Boeckl	427	82	11/8/1976	
	4,267,212	5/12/1981	Sakawaki	427	240	9/19/1979	
	4,347,302	8/31/1982	Gotman	430	270	6/6/1980	
2	4,393,807	7/19/1983	Fujimura, et al.	118	501	9/15/1980	
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2	4-9823	1/1992	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
2	4-104158	4/1992	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
2	5-166712	7/1993	Japan			<input type="checkbox"/>	<input checked="" type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
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17/10/01			3/6/03				

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		APPLICANT Emir Gurer					
		FILING DATE 06/30/2001		GROUP 1762			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
24	4,438,159	3/20/1984	Weber	427	162	3/8/1982	
	4,510,176	4/9/1985	Cuthbert, et al.	427	82	9/26/1983	
	4,518,678	5/21/1985	Allen	430	311	12/16/1983	
	4,600,597	7/15/1986	White, et al.	427	9	10/29/1984	
	4,732,785	3/22/1988	Brewer	427	240	9/26/1986	
	4,741,926	5/3/1988	White, et al.	427	240	10/29/1985	
29	4,800,836	1/31/1989	Yamamoto, et al.	118	52	3/24/1988	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>H. P. ...</i>				DATE CONSIDERED 3/6/03			

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INFORMATION DISCLOSURE CITATION PTO-1449			ATTY. DOCKET NO. 8003-387		SERIAL NO. 09/895,986		
			APPLICANT Emir Gurer		FILING DATE 06/30/2001		
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
24	4,932,353	6/12/1990	Kawata, et al.	118	302	12/5/1988	
	4,946,710	8/7/1990	Miller, et al.	427	126.3	6/2/1987	
	4,963,390	10/16/1990	Lipeles, et al.	427	110	10/5/1988	
	5,013,586	5/7/1991	Cavazza	427	240	9/14/1989	
	5,066,616	11/19/1991	Gordon	437	229	9/7/1990	
	5,094,884	3/10/1992	Hillman, et al.	427	240	4/24/1990	
	5,095,848	3/17/1992	Ikeno	118	53	4/30/1990	
	4,822,639	4/18/1989	Fujii, et al.	427	240	8/21/1987	
	4,886,012	12/12/1989	Ikeno, et al.	118	667	6/27/1988	
24	4,514,440	4/30/1985	Justice, et al.	427	85	12/12/1983	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER			DATE CONSIDERED				

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